STWA20N95K5



N-channel 950 V, 0.275 Ω typ., 17.5 A MDmesh™ K5 Power MOSFET in a TO-247 long leads package

Datasheet - production data

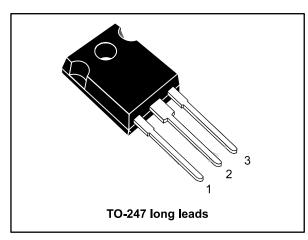
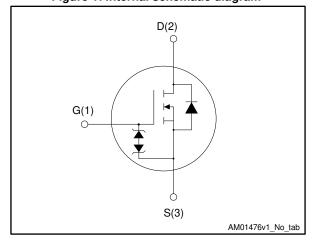


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	I _D	P _{TOT}
STWA20N95K5	950 V	0.330 Ω	17.5 A	250 W

- Industry's lowest R_{DS(on)} x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

Applications

• Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Table 1: Device summary

Order code	Marking	Package	Packing	
STWA20N95K5	20N95K5	TO-247 long leads	Tube	

Contents STWA20N95K5

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STWA20N95K5 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _G s	Gate-source voltage	±30	V
I_{D}	Drain current (continuous) at T _C = 25 °C	17.5	Α
ΙD	Drain current (continuous) at T _C = 100 °C	11	Α
I _D ⁽¹⁾	Drain current (pulsed)	70	Α
P _{TOT}	Total dissipation at T _C = 25 °C	250	W
ESD	Gate-source human body model (R= 1.5 kΩ, C = 100 pF)	2	kV
dv/dt (2)	Peak diode recovery voltage slope	6	\//
dv/dt (3)	MOSFET dv/dt ruggedness	50	V/ns
Tj	Operating junction temperature range	-55 to 150	°C
T _{stg}	Storage temperature range	-55 10 150	C

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	0.5	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	50	°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
lar	Avalanche current, repetitive or not repetitive (pulse width limited by T _{jmax.})		Α
Eas	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	200	mJ

 $[\]ensuremath{^{(1)}}\mbox{Pulse}$ width limited by safe operating area.

 $^{^{(2)}}I_{SD} \le 17.5 \text{ A, di/dt} \le 100 \text{ A/}\mu\text{s; } V_{DS} \text{ peak} \le V_{(BR)DSS}$

 $^{^{(3)}}V_{DS} \le 760 \text{ V}$

Electrical characteristics STWA20N95K5

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 5: On/off-state

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS} Drain-source breakdown voltage		$V_{GS} = 0 V, I_D = 1 mA$	950			V
		$V_{GS} = 0 \text{ V}, V_{DS} = 950 \text{ V}$			1	μΑ
IDSS	Zero-gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 950 \text{ V}$ $T_{C} = 125 {}^{\circ}\text{C}^{(1)}$			50	μΑ
I _{GSS}	Gate body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 100 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 9 \text{ A}$		0.275	0.330	Ω

Notes:

Table 6: Dynamic

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Symbol Parameter		Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		1	1550	1	pF
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, $ $V_{GS} = 0 \text{ V}$	-	140	-	pF
Crss	Reverse transfer capacitance	Vu3 – V V	-	1	-	pF
C _{o(er)} (1)	Equivalent capacitance energy related	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to}$	-	65	-	рF
C _{o(tr)} (2)	Equivalent capacitance time related	760 V		178	1	рF
Rg	Intrinsic gate resistance	f = 1 MHz , I _D = 0 A	ı	3.5	1	Ω
Qg	Total gate charge	$V_{DD} = 760 \text{ V},$	1	48	1	nC
Q_{gs}	Gate-source charge	$I_D = 17.5 A$	-	9	-	nC
Q_{gd}	Gate-drain charge	V _{GS} = 10 V (see Figure 16: "Test circuit for gate charge behavior")	-	32.5	-	nC

Notes:

 $^{^{(1)}\}mbox{Defined}$ by design, not subject to production test

 $^{^{(1)}}$ Co_(er) is a constant capacitance value that gives the same stored energy as Coss while VDS is rising from 0 to 80% VDSS.

 $^{^{(2)}}C_{0(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 7: Switching times

Table 11 curious g unico						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
td(on)	Turn-on delay time	V_{DD} = 475 V, I_{D} = 9 A, R_{G} = 4.7 Ω	-	18	-	ns
tr	Rise time	$V_{GS} = 10 \text{ V}$	-	9	-	ns
t _{d(off)}	Turn-off delay time	(see Figure 15: "Test circuit for resistive load switching times" and Figure 20: "Switching time waveform")	1	65	-	ns
tf	Fall time	,	-	18	-	ns

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		17.5	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		70	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 17.5 A, V _{GS} = 0 V	-		1.5	V
t _{rr}	Reverse recovery time	$I_{SD} = 17.5$ A, $di/dt = 100$ A/ μ s, $V_{DD} = 60$ V (see Figure 17: "Test circuit for	-	513		ns
Qrr	Reverse recovery charge		-	12		μC
I _{RRM}	Reverse recovery current	inductive load switching and diode recovery times")	-	46		Α
trr	Reverse recovery time	I _{SD} = 17.5 A, di/dt = 100 A/μs V _{DD} = 60 V, T _j = 150 °C (see Figure 17: "Test circuit for inductive load switching and diode recovery times")	-	670		ns
Q _{rr}	Reverse recovery charge		-	15		μC
I _{RRM}	Reverse recovery current		-	44		Α

Notes:

Table 9: Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _(BR) GSO	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}, I_{D} = 0 \text{ A}$	30	-	-	V

The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.



⁽¹⁾Pulse width limited by safe operating area

 $^{^{(2)}}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)

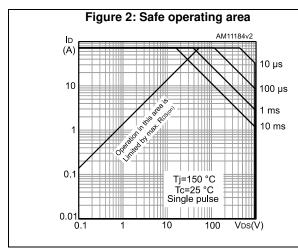
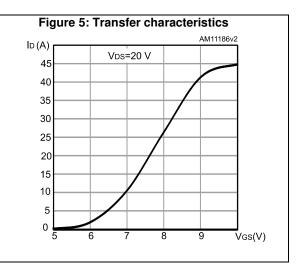
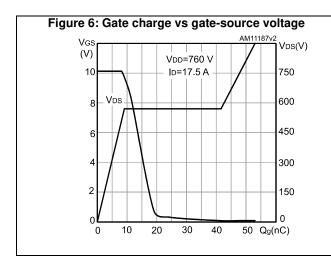


Figure 3: Thermal impedance GC18460 K $\delta = 0.5$ 0.2 0.2 0.02 0.01 0.05 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.05 0.02 0.01 0.02 0.0

Figure 4: Output characteristics AM11185v2 **I**□ (A) Vgs=11 V 9 V 40 35 30 8 V 25 20 15 7 V 10 6 V 10 15 V_Ds(V)





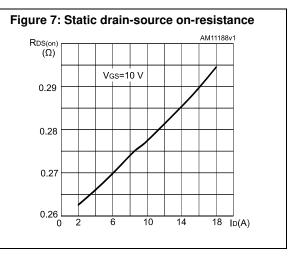


Figure 8: Capacitance variation

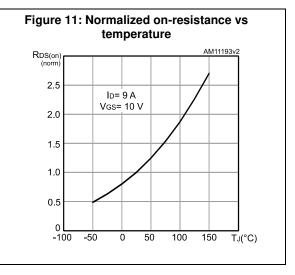
C (pF)
10000
1000
1000
Ciss
Coss
Crss
10
0.1
1 1 10 100 Vbs(V)

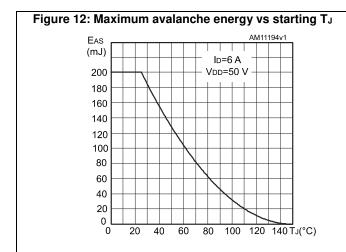
Eoss(µJ)

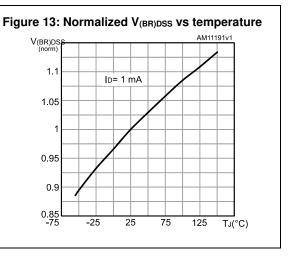
AM11190v2

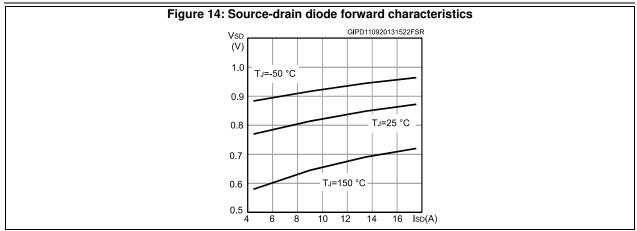
26
24
22
20
18
16
14
12
10
8
6
4
2
20
0
200
400
600
800
Vbs(V)

Figure 10: Normalized gate threshold voltage vs temperature AM11192v2 VGS(th) (norm) 1.2 ID= 100 μA 1.1 1.0 0.9 8.0 0.7 0.6 0.5 0.4 0.3 T)(°C) -50 0 50 100 150







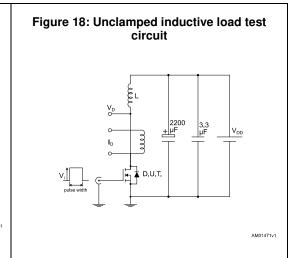


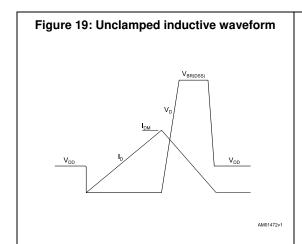
STWA20N95K5 Test circuits

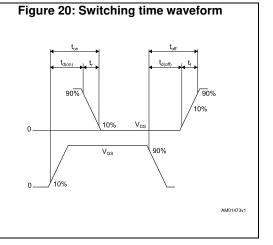
3 Test circuits

Figure 15: Test circuit for resistive load switching times

Figure 17: Test circuit for inductive load switching and diode recovery times







4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-247 long leads package information

HEAT-SINK PLANE øΡ E3 A2-Q Ď A1. *b2* 3 (3x) b 8463846_2_F

Figure 21: TO-247 long leads package outline

Table 10: TO-247 long leads package mechanical data

Dim	J	mm	
Dim.	Min.	Тур.	Max.
Α	4.90	5.00	5.10
A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
b	1.16		1.26
b2			3.25
b3			2.25
С	0.59		0.66
D	20.90	21.00	21.10
E	15.70	15.80	15.90
E2	4.90	5.00	5.10
E3	2.40	2.50	2.60
е	5.34	5.44	5.54
L	19.80	19.92	20.10
L1			4.30
Р	3.50	3.60	3.70
Q	5.60		6.00
S	6.05	6.15	6.25

Revision history STWA20N95K5

Revision history 5

Table 11: Document revision history

Date	Revision	Changes
21-Nov-2013	1	First release.
16-Jan-2017	2	Datasheet promoted from preliminary to production data. Modified: title. Updated: features, applications and description in cover page. Minor text changes in Section 1: "Electrical ratings" and Section 2: "Electrical characteristics". Updated Section 2.1: "Electrical characteristics (curves)". Updated Section 4.1: "TO-247 long leads package information".

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